Hybrid 8j182 Traveler

January 26, 2000

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J182 has die: 187-076 187-077 187-078 187-079 228-006 228-007 228-008 228-009

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j182 classification info. Created 10:40:30 01/24/00

Hybrid 8j182 quality: fair
Chip classification: fair fair good fair fair good good fair
Bad channels (chip-channel): 3-48 4-16
Bad cells: none
Random bad capacitors (chip-cell-channel): 0-10-24 0-16-90 1-3-120
   1-3-121 3-34-112 7-0-38 7-13-38 7-13-39 7-14-38 7-2-38 7-26-38
   7-4-38 7-43-38
Channels at pedestal needed for DCMS: 34.7 33.7 34.7 33.6 29.6 30.6 30.6 30.6
```

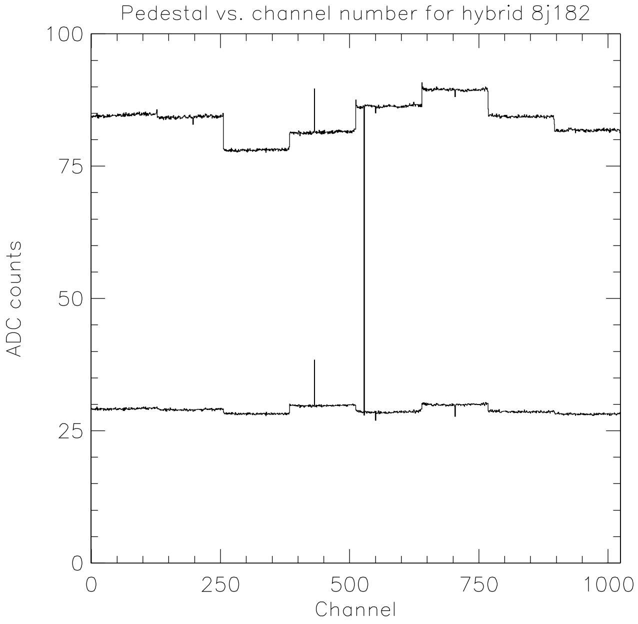
4 Comments

Encapsulated. FE DV finger gold bonds. HV tested.

5 Pedestal

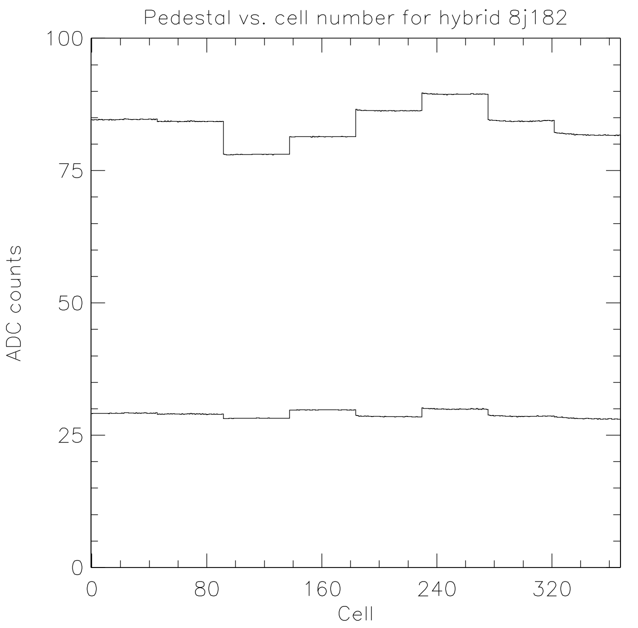
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

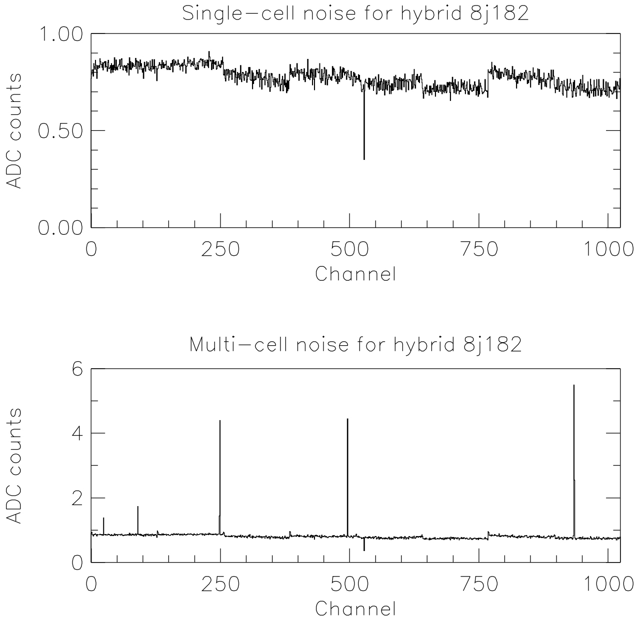
Pedestal vs. Pipeline Cell ID



6 Noise

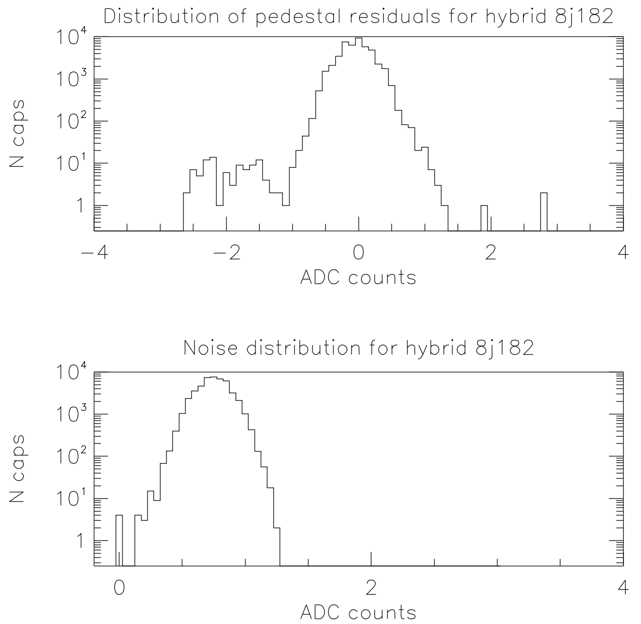
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise



The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in